Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/560,215	LEVCHIN ET AL.	
Examiner	Art Unit	
Alain L. Bashore	1762	

SEAR	CHED	
Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
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DATE 10/6/2005	AB
10/6/2005	АВ